

REMARKS

No new matter has been added. The Applicant again requests entry of the amendments as set forth in the Appendices hereto prior to examination of the application on the merits.

Respectfully submitted,

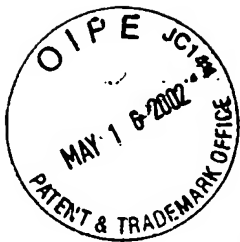


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Date: May 13, 2002

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MAY 20 2002
GROUP 3600

Serial No.: 10/092,185

VERSION OF CLAIMS WITH MARKINGS TO SHOW CHANGES MADE

2. (Amended) A reliability testing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:
storing [an]a reliability testing flag associated with a unique identification code of each integrated circuit device of the plurality of integrated circuit devices for indicating whether each integrated circuit device requires further reliability testing;
automatically reading the unique identification code of each integrated circuit device of the plurality of integrated circuit devices;
accessing the reliability testing flag stored for each unique identification code of each integrated circuit device;
sorting the plurality of integrated circuit devices in accordance with whether their reliability testing flag indicates they are in need of the further reliability testing; and
performing the further reliability testing for the integrated circuit devices requiring the further reliability testing.

3. (Amended) A manufacturing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:
storing a reliability testing flag associated with a unique identification code of each integrated circuit device of the plurality of integrated circuit devices for indicating whether each integrated circuit device requires further reliability testing;
automatically reading the unique identification code of each integrated circuit device of the plurality of integrated circuit devices;
accessing the reliability testing flag stored for each unique identification code of each integrated circuit device;
sorting the plurality of integrated circuit devices in accordance with whether their reliability testing flag indicates they are in need of the further reliability testing; and
performing the further reliability testing for the integrated circuit devices requiring the further reliability testing.